

## TPS20xxB-Q1 限流、配电开关

### 1 特性

- 符合汽车应用要求
- 具有符合 AEC-Q100 标准的下列特性：
  - 器件温度等级 1：-40°C 至 125°C 的环境工作温度范围
  - 器件 HBM ESD 分类等级 2
  - 器件 CDM ESD 分类等级 C6
  - 器件 MM ESD 分类等级 M0
- 105mΩ 高侧 MOSFET
- 500mA 持续电流
- 散热和短路保护
- 精确的电流限制：0.75A (最小值)，1.25A (最大值)
- 工作范围：2.7V 至 5.5V
- 上升时间典型值 0.6ms
- 欠压锁定
- 抗尖峰脉冲故障报告 ( $\overline{OC}$ )
- 上电期间无  $\overline{OC}$  尖峰脉冲
- 最大待机电源电流：1μA (单、双通道) 或 2μA (三、四通道)
- 双向开关
- UL 认可文件编号 E169910

### 2 应用

- 大电容负载
- 短路保护

### 3 说明

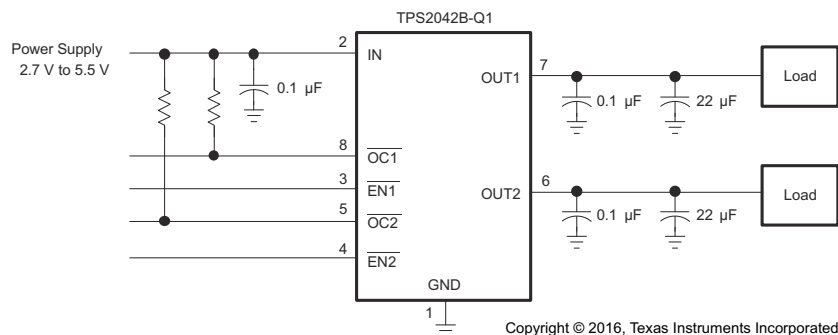
TPS20xxB-Q1 配电开关用于有可能发生高容性负载和短路的应用。该款器件组装有用于配电系统的 105mΩ N 通道 MOSFET 电源开关。此类系统要求在单一封装内具有多个电源开关。每个开关由一个逻辑使能输入控制。栅极驱动由一个内部电荷泵提供，此电荷泵设计用于控制电源开关上升时间和下降时间以大大减少切换期间的电流涌入。电荷泵无需外部组件并可在低至 2.7V 的电源电压下工作。

当输出负载超过限流阈值或者短路出现时，该器件通过切换至恒定电流模式，并通过将过流 ( $\overline{OCx}$ ) 下拉至逻辑输出低电平来将输出电流限制在安全水平上。如果持续重过载和短路增加了开关内的功率耗散，则将引起结温上升，此时，过热保护电路将关闭此开关以避免器件损坏。一旦器件充分冷却，此器件将自动从热关断中恢复。内部电路确保此开关在有效输入电压出现前保持关闭状态。此配电开关旨在将电流限制设置为 1A (典型值)。

#### 器件信息<sup>(1)</sup>

器件型号	封装	封装尺寸 (标称值)
TPS2041B-Q1	SOT-23 (5)	2.80 mm × 2.90 mm
TPS2042B-Q1、TPS2051B-Q1	SOIC (8)	4.90mm × 6.00mm

(1) 如需了解所有可用封装，请参阅数据表末尾的可订购产品附录。



典型应用原理图



## Table of Contents

1 特性.....	1	9 Application and Implementation.....	14
2 应用.....	1	9.1 Application Information.....	14
3 说明.....	1	9.2 Typical Applications.....	14
4 Revision History.....	2	10 Power Supply Recommendations.....	21
5 Pin Configuration and Functions.....	3	11 Layout.....	22
6 Specifications.....	4	11.1 Layout Guidelines.....	22
6.1 Absolute Maximum Ratings.....	4	11.2 Layout Example.....	22
6.2 ESD Ratings.....	4	11.3 Thermal Considerations.....	22
6.3 Recommended Operating Conditions.....	5	12 Device and Documentation Support.....	23
6.4 Thermal Information.....	5	12.1 Related Links.....	23
6.5 Electrical Characteristics.....	5	12.2 接收文档更新通知.....	23
6.6 Typical Characteristics.....	8	12.3 支持资源.....	23
7 Parameter Measurement Information.....	10	12.4 Trademarks.....	23
8 Detailed Description.....	11	12.5 静电放电警告.....	23
8.1 Overview.....	11	12.6 术语表.....	23
8.2 Functional Block Diagrams.....	11	13 Mechanical, Packaging, and Orderable	
8.3 Feature Description.....	12	Information.....	23
8.4 Device Functional Modes.....	13		

## 4 Revision History

注：以前版本的页码可能与当前版本的页码不同

Changes from Revision C (September 2016) to Revision D (October 2020)	Page
• 更新了整个文档中的表格、图和交叉参考的编号格式.....	1
• 将特性列表中的“70mΩ 高侧 MOSFET”更改为“105mΩ 高侧 MOSFET”.....	1
• 将描述部分中的“70mΩ 高侧 MOSFET”更改为“105mΩ 高侧 MOSFET”.....	1
• Updated $r_{DS(ON)}$ TYP and MAX values in the <i>Electrical Characteristics</i> table.....	5
• Updated 图 6-9.....	8
• Changed "70-mΩ High-Side MOSFET" to "105-mΩ High-Side MOSFET" in the <i>Overview</i> section.....	11
Changes from Revision B (October 2011) to Revision C (September 2016)	Page
• 添加了 ESD 等级表、特性说明部分、器件功能模式、应用和实施部分、电源相关建议部分、布局部分、器件和文档支持部分以及机械、封装和可订购信息部分.....	1
• 删除了订购信息表；请参阅数据表末尾的 POA.....	1
• 删除了通用交换机目录图.....	1
• 添加了符合 AEC-Q100 标准的项目符号.....	1
• Added <i>Thermal Information</i> table.....	5
• Deleted <i>Dissipation Ratings</i> section.....	8
• Combined Functional Block Diagrams for TPS2041B-Q1 and TPS2051B-Q1 as they are the same.....	11
Changes from Revision A (June 2010) to Revision B (October 2011)	Page
• 更改了可订购器件型号：将 TPS2041QDBVRQ1 更改为 TPS2041BQDBVRQ1.....	1
Changes from Revision * (November 2007) to Revision A (June 2010)	Page
• 添加了 TPS2041B-Q1 器件信息.....	1

## 5 Pin Configuration and Functions

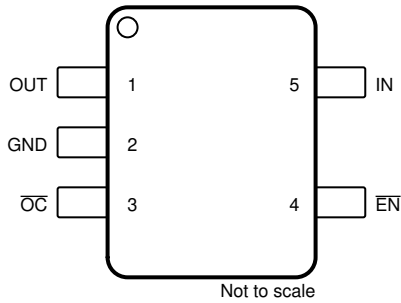


图 5-1. TPS2041B-Q1 DBV Package 5-Pin SOT-23 Top View

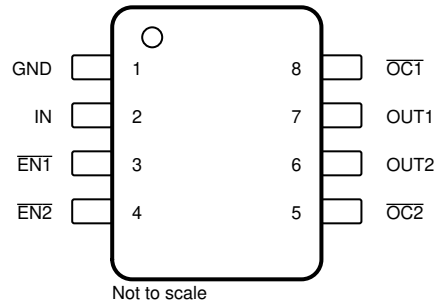


图 5-2. TPS2042B-Q1 D Package 8-Pin SOIC Top View

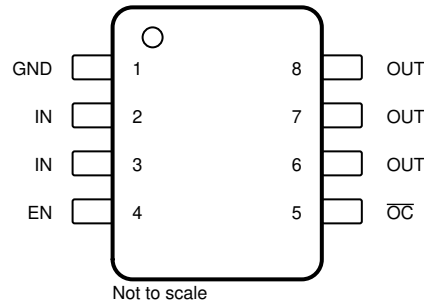


图 5-3. TPS2051B-Q1 D Package 8-Pin SOIC Top View

表 5-1. Pin Functions: TPS2041B-Q1

PIN		TYPE	DESCRIPTION
NAME	NO.		
EN	4	I	Enable input, logic low turns on power switch
GND	2	GND	Ground
IN	5	PWR	Supply input voltage
OC	3	O	Overcurrent, open-drain output, active low
OUT	1	O	Power-switch output

表 5-2. Pin Functions: TPS2042B-Q1

PIN		TYPE	DESCRIPTION
NAME	NO.		
EN1	3	I	Enable input, logic low turns on power switch IN-OUT1
EN2	4	I	Enable input, logic low turns on power switch IN-OUT2
GND	1	GND	Ground
IN	2	PWR	Supply input voltage
OC1	8	O	Overcurrent, open-drain output, active low, IN-OUT1
OC2	5	O	Overcurrent, open-drain output, active low, IN-OUT2

表 5-2. Pin Functions: TPS2042B-Q1 (continued)

PIN		TYPE	DESCRIPTION
NAME	NO.		
OUT1	7	O	Power-switch output, IN-OUT1
OUT2	6	O	Power-switch output, IN-OUT2

表 5-3. Pin Functions: TPS2051B-Q1

PIN		TYPE	DESCRIPTION
NAME	NO.		
EN	4	I	Enable input, logic high turns on power switch
GND	1	GND	Ground
IN	2, 3	PWR	Supply input voltage
$\overline{OC}$	5	O	Overcurrent open-drain output, active low
OUT	6, 7, 8	O	Power-switch output

## 6 Specifications

### 6.1 Absolute Maximum Ratings

over operating free-air temperature range unless otherwise noted<sup>(1)</sup>

		MIN	MAX	UNIT
Input voltage <sup>(2)</sup>	IN	- 0.3	6	V
Output voltage <sup>(2)</sup>	OUT, OUTx	- 0.3	6	V
Input voltage	ENx, EN	- 0.3	6	V
Voltage, $V_{I(\overline{OC})}$ , $V_{I(\overline{OCx})}$	$\overline{OC}$ , $\overline{OCx}$	- 0.3	6	V
Continuous output current			Internally limited	
Continuous total power dissipation			See <a href="#">ESD Ratings</a>	
Operating virtual-junction temperature, $T_J$		- 40	125	°C
Storage temperature, $T_{stg}$		- 65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages are with respect to GND.

### 6.2 ESD Ratings

		VALUE	UNIT
TPS2041B-Q1 in DBV Package and TPS2042B-Q1 in D package			
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002 <sup>(1)</sup>	±2500
		Charged-device model (CDM), per AEC Q100-011	±1500
		Machine model (MM), per AEC Q100-003	±50
TPS2051B-Q1 in D package			
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002 <sup>(1)</sup>	±2000
		Charged-device model (CDM), per AEC Q100-011	±1500
		Machine model (MM), per AEC Q100-003	±50

- (1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

### 6.3 Recommended Operating Conditions

		MIN	MAX	UNIT
$V_{I(IN)}$	Input voltage (IN)	2.7	5.5	V
$V_{I(EN\bar{x})}$ , $V_{I(EN)}$	Input voltage ( $\bar{ENx}$ , EN)	0	5.5	V
$I_{O(OUT)}$ , $I_{O(OUTx)}$	Continuous output current (OUT, OUTx)	0	500	mA
$T_J$	Operating virtual-junction temperature	-40	125	°C

### 6.4 Thermal Information

THERMAL METRIC <sup>(1)</sup>		TPS2041B-Q1	TPS2042B-Q1	TPS2051B-Q1	UNIT
		DBV (SOT-23)	D (SOIC)	D (SOIC)	
		5 PINS	8 PINS	8 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	224.1	117.2	124.5	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	131.2	63.3	72.7	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	55.4	57.5	64.9	°C/W
$\psi_{JT}$	Junction-to-top characterization parameter	19.2	15.3	24.7	°C/W
$\psi_{JB}$	Junction-to-board characterization parameter	54.3	37	64.4	°C/W

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

### 6.5 Electrical Characteristics

over recommended operating junction temperature range,  $V_{I(IN)} = 5.5\text{ V}$ ,  $I_O = 0.5\text{ A}$ ,  $V_{I(EN\bar{x})} = 0\text{ V}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS <sup>(1)</sup>		MIN	TYP	MAX	UNIT
<b>POWER SWITCH</b>							
$r_{DS(ON)}$	Static drain-source on-state resistance, 5-V or 3.3-V operation	$V_{I(IN)} = 5\text{ V}$ or $3.3\text{ V}$ , $I_O = 0.5\text{ A}$	$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$		105	160	m $\Omega$
	Static drain-source on-state resistance, 2.7-V operation <sup>(2)</sup>	$V_{I(IN)} = 2.7\text{ V}$ , $I_O = 0.5\text{ A}$	$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$		110	175	
$t_r$	Rise time, output <sup>(2)</sup>	$V_{I(IN)} = 5.5\text{ V}$	$C_L = 1\text{ }\mu\text{F}$ , $R_L = 10\text{ }\Omega$	$T_J = 25^\circ\text{C}$	0.6	1.5	ms
		$V_{I(IN)} = 2.7\text{ V}$			0.4	1	
$t_f$	Fall time, output <sup>(2)</sup>	$V_{I(IN)} = 5.5\text{ V}$	$C_L = 1\text{ }\mu\text{F}$ , $R_L = 10\text{ }\Omega$	$T_J = 25^\circ\text{C}$	0.05	0.5	ms
		$V_{I(IN)} = 2.7\text{ V}$			0.05	0.5	
<b>ENABLE INPUT (<math>\bar{EN}</math>, <math>ENx</math>)</b>							
$V_{IH}$	High-level input voltage	$2.7\text{ V} \leq V_{I(IN)} \leq 5.5\text{ V}$		2			V
$V_{IL}$	Low-level input voltage	$2.7\text{ V} \leq V_{I(IN)} \leq 5.5\text{ V}$				0.8	
$I_I$	Input current	$V_{I(EN\bar{x})} = 0\text{ V}$ or $5.5\text{ V}$		-0.5		0.5	$\mu\text{A}$
$t_{on}$	Turnon time <sup>(2)</sup>	$C_L = 100\text{ }\mu\text{F}$ , $R_L = 10\text{ }\Omega$				3	ms
$t_{off}$	Turnoff time <sup>(2)</sup>	$C_L = 100\text{ }\mu\text{F}$ , $R_L = 10\text{ }\Omega$				10	
<b>CURRENT LIMIT</b>							
$I_{OS}$	Short-circuit output current	$V_{I(IN)} = 5\text{ V}$ , OUT connected to GND, device enabled into short-circuit	$T_J = 25^\circ\text{C}$	0.65	1	1.25	A
			$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$	0.6	1	1.3	
<b>SUPPLY CURRENT (TPS2041B-Q1, TPS2051B-Q1)</b>							
	Supply current, low-level output	No load on OUT, $V_{I(EN)} = 5.5\text{ V}$ or $V_{I(EN)} = 0\text{ V}$	$T_J = 25^\circ\text{C}$	0.5	1	$\mu\text{A}$	
			$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$	0.5	5		
	Supply current, high-level output	No load on OUT, $V_{I(EN)} = 0\text{ V}$ or $V_{I(EN)} = 5.5\text{ V}$	$T_J = 25^\circ\text{C}$	43	60	$\mu\text{A}$	
			$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$	43	70		
	Leakage current	OUT connected to ground, $V_{I(EN)} = 5.5\text{ V}$ or $V_{I(EN)} = 0\text{ V}$	$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$	1		$\mu\text{A}$	

## 6.5 Electrical Characteristics (continued)

over recommended operating junction temperature range,  $V_{I(IN)} = 5.5\text{ V}$ ,  $I_O = 0.5\text{ A}$ ,  $V_{I(EN\bar{x})} = 0\text{ V}$  (unless otherwise noted)

PARAMETER	TEST CONDITIONS <sup>(1)</sup>		MIN	TYP	MAX	UNIT
Reverse leakage current	$V_{I(OUTx)} = 5.5\text{ V}$ , $I_N = \text{ground}^{(2)}$	$T_J = 25^\circ\text{C}$		0		$\mu\text{A}$

## 6.5 Electrical Characteristics (continued)

over recommended operating junction temperature range,  $V_{I(IN)} = 5.5\text{ V}$ ,  $I_O = 0.5\text{ A}$ ,  $V_{I(EN\bar{x})} = 0\text{ V}$  (unless otherwise noted)

PARAMETER	TEST CONDITIONS <sup>(1)</sup>	MIN	TYP	MAX	UNIT
<b>SUPPLY CURRENT (TPS2042B-Q1)</b>					
Supply current, low-level output	No load on OUT, $V_{I(EN\bar{x})} = 5.5\text{ V}$	$T_J = 25^\circ\text{C}$	0.5	1	$\mu\text{A}$
		$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$	0.5	5	
Supply current, high-level output	No load on OUT, $V_{I(EN\bar{x})} = 0\text{ V}$	$T_J = 25^\circ\text{C}$	50	70	$\mu\text{A}$
		$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$	50	90	
Leakage current	OUT connected to ground, $V_{I(EN\bar{x})} = 5.5\text{ V}$		1		$\mu\text{A}$
Reverse leakage current	$V_{I(OUTx)} = 5.5\text{ V}$ , IN = ground <sup>(2)</sup>		0.2		$\mu\text{A}$
<b>UNDERVOLTAGE LOCKOUT</b>					
Low-level input voltage, IN, INx		2		2.5	V
Hysteresis, IN, INx	$T_J = 25^\circ\text{C}$		75		mV
<b>OVERCURRENT ( <math>\overline{\text{OC}}</math>, <math>\overline{\text{OCx}}</math> )</b>					
Output low voltage, $V_{OL(\overline{\text{OCx}})}$	$I_{O(\overline{\text{OCx}})} = 5\text{ mA}$			0.4	V
OFF-state current <sup>(2)</sup>	$V_{O(\overline{\text{OCx}})} = 5\text{ V}$ or $3.3\text{ V}$			1	$\mu\text{A}$
$\overline{\text{OC}}$ deglitch <sup>(2)</sup>	$\overline{\text{OCx}}$ assertion or deassertion	4	8	15	ms
<b>THERMAL SHUTDOWN<sup>(3)</sup></b>					
Thermal shutdown threshold <sup>(2)</sup>		135			$^\circ\text{C}$
Recovery from thermal shutdown <sup>(2)</sup>		125			$^\circ\text{C}$
Hysteresis <sup>(2)</sup>			10		$^\circ\text{C}$

- (1) Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be accounted for separately.
- (2) Specified by design.
- (3) The thermal shutdown only reacts under overcurrent conditions.

## 6.6 Typical Characteristics

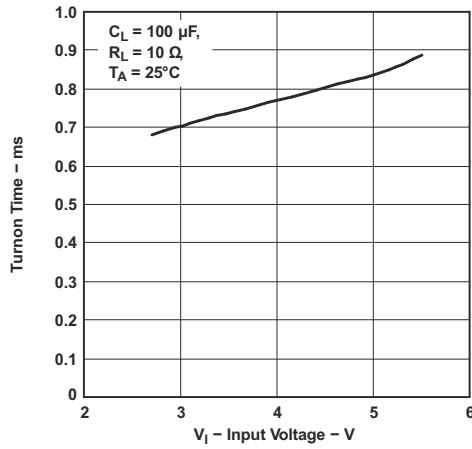


图 6-1. Turnon Time vs Input voltage

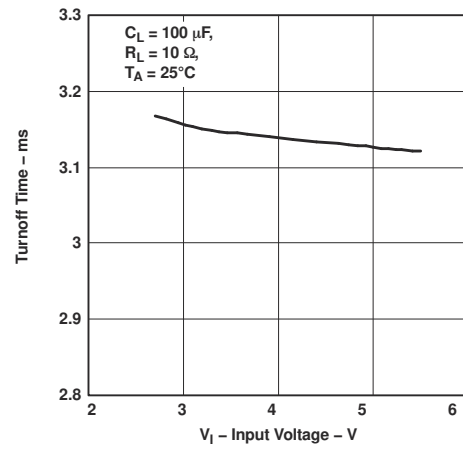


图 6-2. Turnoff Time vs Input Voltage

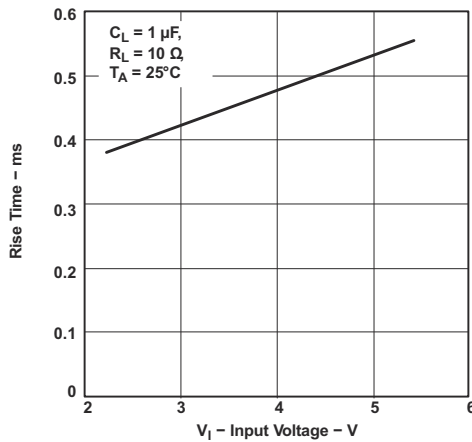


图 6-3. Rise Time vs Input Voltage

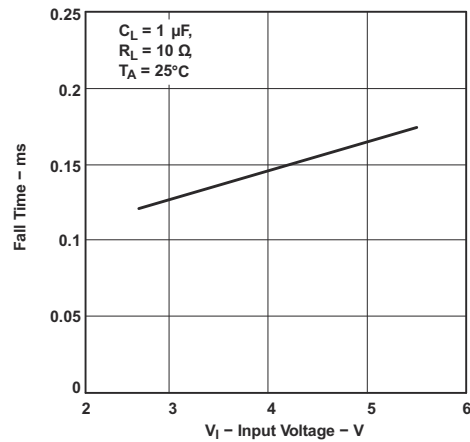


图 6-4. Fall Time vs Input Voltage

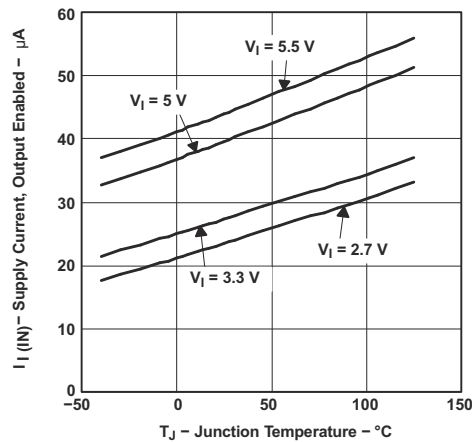


图 6-5. TPS2041B-Q1 and TPS2051B-Q1 Supply Current, Output Enabled vs Junction Temperature

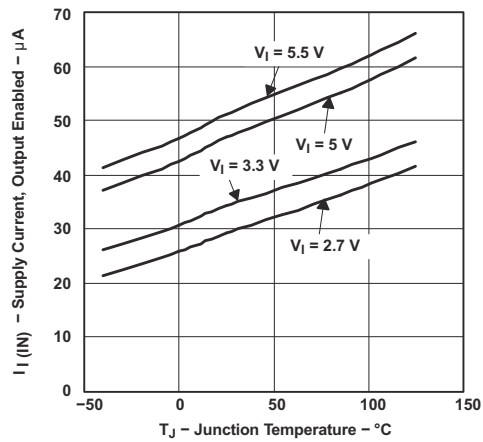


图 6-6. TPS2042B-Q1 Supply Current, Output Enabled vs Junction Temperature



### 6.6 Typical Characteristics (continued)

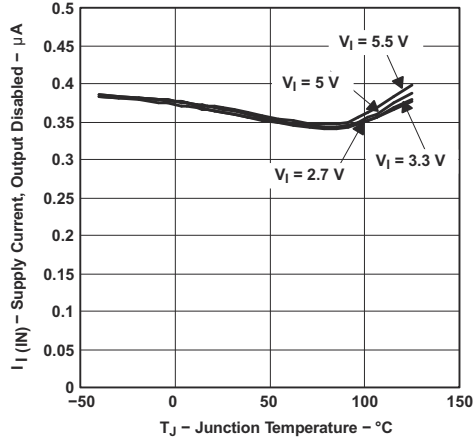


图 6-7. TPS2041B-Q1 and TPS2051B-Q1 Supply Current, Output Disabled vs Junction Temperature

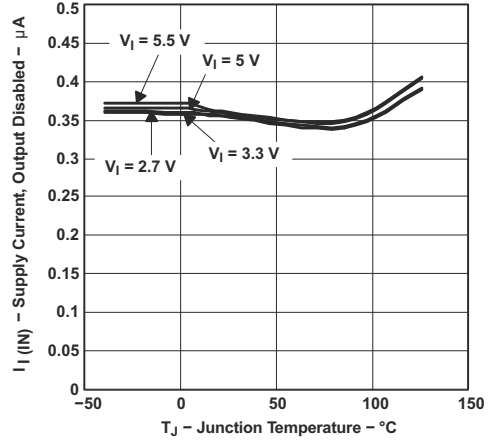


图 6-8. TPS2042B-Q1 Supply Current, Output Disabled vs Junction Temperature

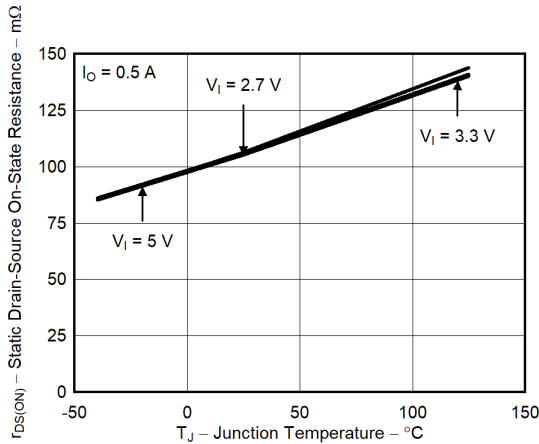


图 6-9. Static Drain-Source ON-state Resistance vs Junction Temperature

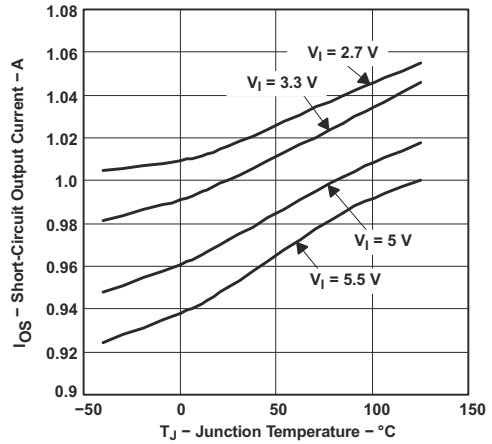


图 6-10. Short-Circuit Output Current vs Junction Temperature

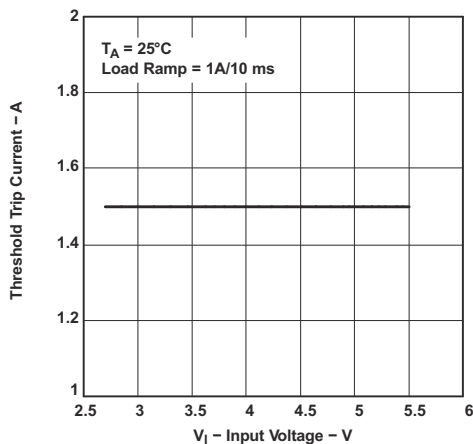


图 6-11. Threshold Trip Current vs Input Voltage

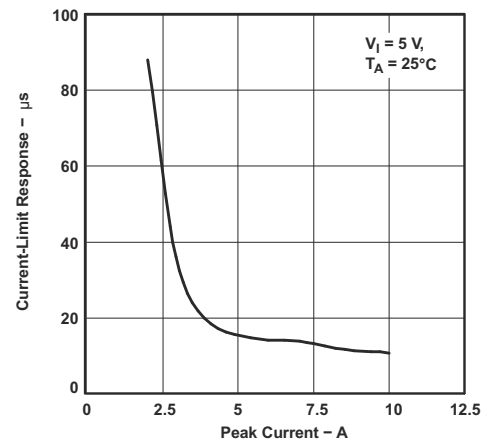
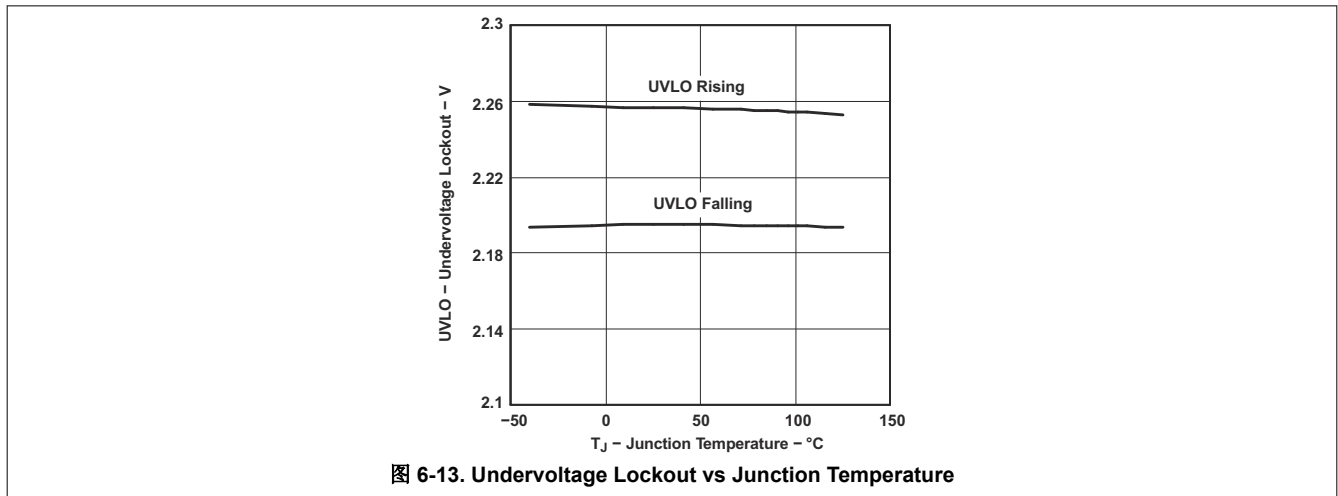
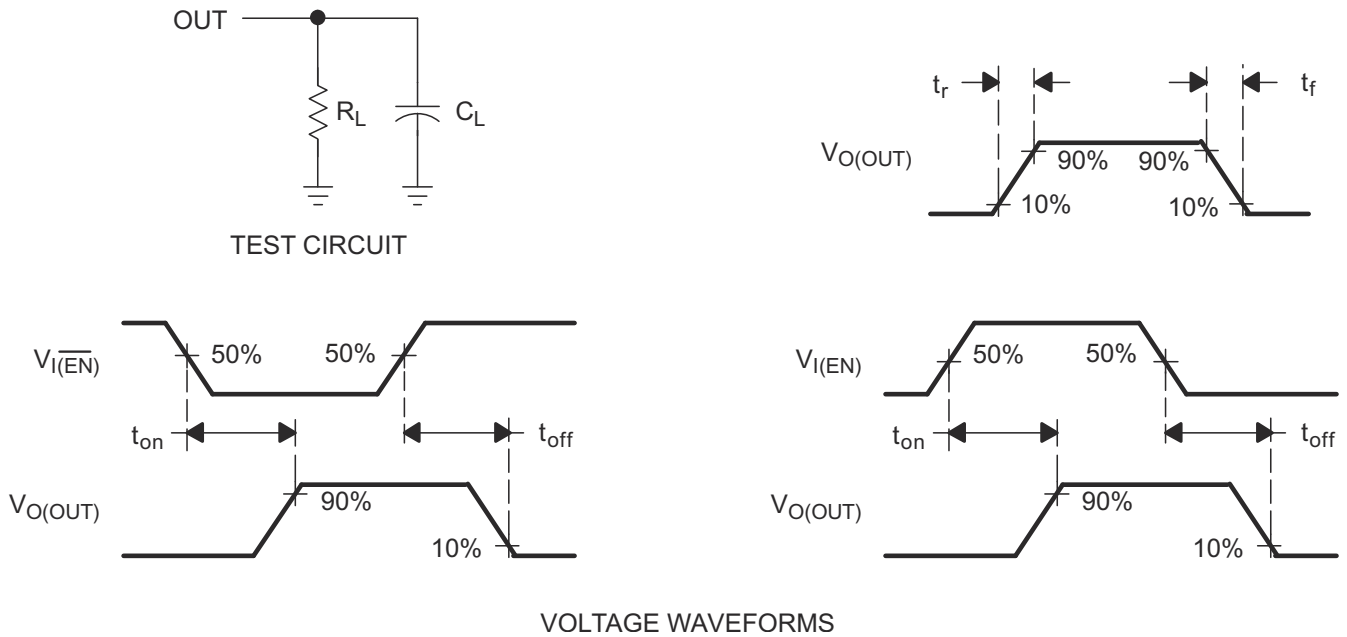


图 6-12. Current-Limit Response vs Peak Current

## 6.6 Typical Characteristics (continued)



## 7 Parameter Measurement Information



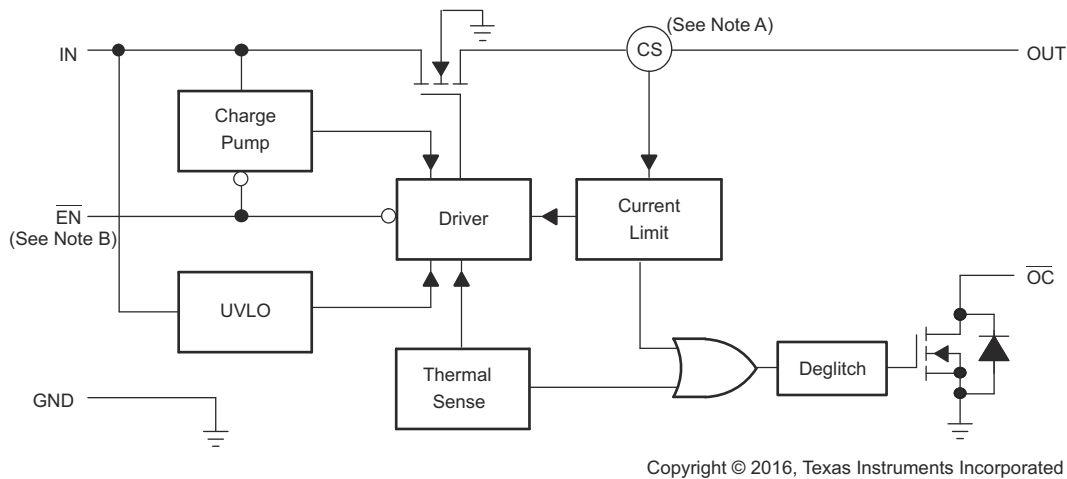
**图 7-1. Test Circuit and Voltage Waveforms**

## 8 Detailed Description

### 8.1 Overview

The TPS20xxB-Q1 devices are current-limited, power-distribution switches providing 0.5-A continuous-load current. These devices incorporate 105-mΩ N-channel MOSFET power switches for power-distribution systems that require multiple power switches in a single package. A gate driver is provided by an internal charge pump designed to minimize current surges during switching. The charge pump requires no external components and allows operation supplies as low as 2.7 V.

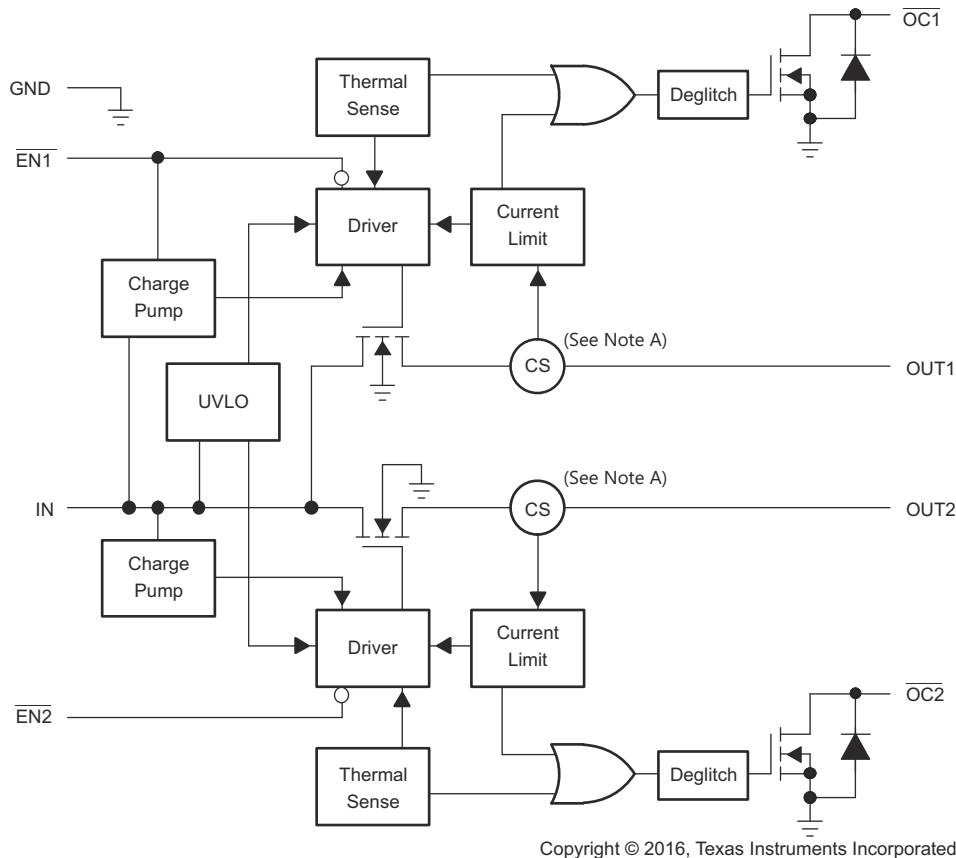
### 8.2 Functional Block Diagrams



Copyright © 2016, Texas Instruments Incorporated

- A. CS = Current sense
- B. EN = Active low ( $\overline{\text{EN}}$ ) for TPS2041B-Q1; Active high (EN) for TPS2051B-Q1

**图 8-1. Functional Block Diagram (TPS2041B-Q1 and TPS2051B-Q1)**



A. CS = Current sense

图 8-2. Functional Block Diagram (TPS2042B-Q1)

## 8.3 Feature Description

### 8.3.1 Power Switch

The power switch is an N-channel MOSFET with a low ON-state resistance. Configured as a high-side switch, the power switch prevents current flow from OUT to IN and IN to OUT when disabled. The power switch supplies a minimum current of 500 mA.

### 8.3.2 Charge Pump

An internal charge pump supplies power to the driver circuit and provides the necessary voltage to pull the gate of the MOSFET above the source. The charge pump operates from input voltages as low as 2.7 V and requires little supply current.

### 8.3.3 Driver

The driver controls the gate voltage of the power switch. To limit large current surges and reduce the associated electromagnetic interference (EMI) produced, the driver incorporates circuitry that controls the rise times and fall times of the output voltage.

### 8.3.4 Enable ( $\overline{ENx}$ )

The logic enable pin disables the power switch and the bias for the charge pump, driver, and other circuitry to reduce the supply current. The supply current is reduced to less than 1  $\mu$ A or 2  $\mu$ A when a logic high is present on  $\overline{EN}$ . A logic zero input on  $\overline{EN}$  restores bias to the drive and control circuits and turns the switch on. The enable input is compatible with both TTL and CMOS logic levels.

### 8.3.5 Enable (EN)

The logic enable disables the power switch and the bias for the charge pump, driver, and other circuitry to reduce the supply current. The supply current is reduced to less than 1  $\mu\text{A}$  or 2  $\mu\text{A}$  when a logic low is present on EN. A logic high input on EN restores bias to the drive and control circuits and turns the switch on. The enable input is compatible with both TTL and CMOS logic levels.

### 8.3.6 Overcurrent ( $\overline{\text{OCx}}$ )

The  $\overline{\text{OCx}}$  open-drain output is asserted (active low) when an overcurrent or overtemperature condition is encountered. The output remains asserted until the overcurrent or overtemperature condition is removed. A 10-ms deglitch circuit prevents the  $\overline{\text{OCx}}$  signal from oscillation or false triggering. If an overtemperature shutdown occurs, the  $\overline{\text{OCx}}$  is asserted instantaneously.

### 8.3.7 Current Sense

A sense FET monitors the current supplied to the load. The sense FET measures current more efficiently than conventional resistance methods. When an overload or short circuit is encountered, the current-sense circuitry sends a control signal to the driver. The driver in turn reduces the gate voltage and drives the power FET into its saturation region, which switches the output into a constant-current mode and holds the current constant while varying the voltage on the load.

### 8.3.8 Thermal Sense

Thermal protection prevents damage to the IC when heavy-overload or short-circuit faults are present for extended periods of time. The TPS204xB-Q1 and TPS205xB-Q1 implement a thermal sensing to monitor the operating junction temperature of the power distribution switch. In an overcurrent or short-circuit condition, the junction temperature rises due to excessive power dissipation. Once the die temperature rises to approximately 140°C due to overcurrent conditions, the internal thermal sense circuitry turns the power switch off, thus preventing the power switch from damage. Hysteresis is built into the thermal sense circuit, and after the device has cooled approximately 10°C, the switch turns back on. The switch continues to cycle in this manner until the load fault or input power is removed. The  $\overline{\text{OCx}}$  open-drain output is asserted (active low) when an overtemperature shutdown or overcurrent occurs.

### 8.3.9 Undervoltage Lockout (UVLO)

A voltage sense circuit monitors the input voltage. When the input voltage is below approximately 2 V, a control signal turns off the power switch.

## 8.4 Device Functional Modes

表 8-1 lists OUT pin state as determined by the  $\overline{\text{EN}}$  pin.

表 8-1. OUT Pin State

EN	TPS2041B-Q1	TPS2042B-Q1	TPS2051B-Q1
Low	IN	Open	Open
High	Open	IN	IN

## 9 Application and Implementation

### 备注

以下应用部分的信息不属于 TI 组件规范，TI 不担保其准确性和完整性。客户应负责确定 TI 组件是否适用于其应用。客户应验证并测试其设计，以确保系统功能。

### 9.1 Application Information

#### 9.1.1 Universal Serial Bus (USB) Applications

The universal serial bus (USB) interface is a 12-Mbps, or 1.5-Mbps, multiplexed serial bus designed for low-to-medium bandwidth PC peripherals (for example, keyboards, printers, scanners, and mice). The four-wire USB interface is conceived for dynamic attach-detach (hot plug-unplug) of peripherals. Two lines are provided for differential data, and two lines are provided for 5-V power distribution.

USB data is a 3.3-V level signal, but power is distributed at 5 V to allow for voltage drops in cases where power is distributed through more than one hub across long cables. Each function must provide its own regulated 3.3 V from the 5-V input or its own internal power supply.

The USB specification defines the following five classes of devices, each differentiated by power-consumption requirements:

- Hosts and self-powered hubs (SPHs)
- Bus-powered hubs (BPHs)
- Low-power bus-powered functions
- High-power bus-powered functions
- Self-powered functions

Self-powered and bus-powered hubs distribute data and power to downstream functions. The TPS204xB-Q1 and TPS205xB-Q1 can provide power-distribution solutions to many of these classes of devices.

### 9.2 Typical Applications

#### 9.2.1 TPS2042B-Q1 Typical Application

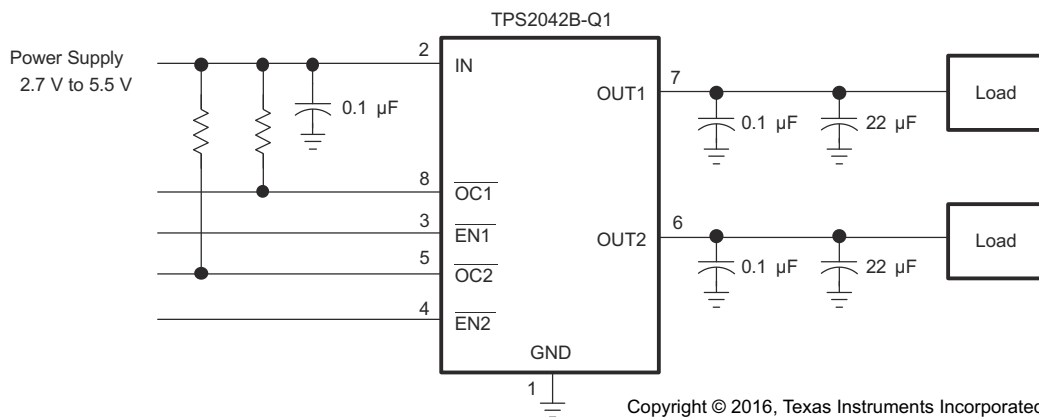


图 9-1. Typical Application Schematic Using the TPS2042B-Q1

### 9.2.1.1 Design Requirements

For this design example, use the parameters listed in 表 9-1 as the input parameters.

表 9-1. Design Parameters

PARAMETER	VALUE
Input voltage	5 V
Output1 voltage	5 V
Output2 voltage	5 V
Output1 current	0.5 A
Output2 current	0.5 A

### 9.2.1.2 Detailed Design Procedure

#### 9.2.1.2.1 Overcurrent

A sense FET is employed to check for overcurrent conditions. Unlike current-sense resistors, sense FETs do not increase the series resistance of the current path. When an overcurrent condition is detected, the device maintains a constant output current and reduces the output voltage accordingly. Complete shutdown occurs only if the fault is present long enough to activate thermal limiting.

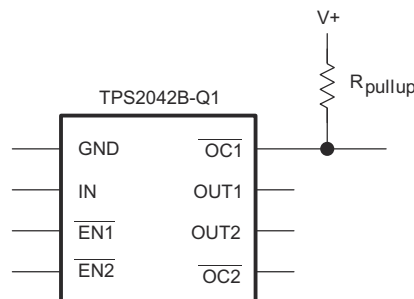
Three possible overload conditions can occur. In the first condition, the output has been shorted before the device is enabled or before  $V_{I(IN)}$  has been applied (see 图 9-7 through 图 9-10). The TPS20xxB-Q1 senses the short and immediately switches into a constant-current output.

In the second condition, a short or an overload occurs while the device is enabled. At the instant the overload occurs, high currents may flow for a short period of time before the current-limit circuit can react. After the current-limit circuit has tripped (reached the overcurrent trip threshold), the device switches into constant-current mode.

In the third condition, the load has been gradually increased beyond the recommended operating current. The current is permitted to rise until the current-limit threshold is reached or until the thermal limit of the device is exceeded (see 图 6-7 through 图 6-8). The TPS20xxB-Q1 is capable of delivering current up to the current-limit threshold without damaging the device. Once the threshold has been reached, the device switches into its constant-current mode.

#### 9.2.1.2.2 $\overline{OC}$ Response

The  $\overline{OCx}$  open-drain output is asserted (active low) when an overcurrent or overtemperature shutdown condition is encountered after a 10-ms deglitch timeout. The output remains asserted until the overcurrent or overtemperature condition is removed. Connecting a heavy capacitive load to an enabled device can cause a momentary overcurrent condition; however, no false reporting on  $\overline{OCx}$  occurs due to the 10-ms deglitch circuit. The TPS20xxB-Q1 is designed to eliminate false overcurrent reporting. The internal overcurrent deglitch eliminates the need for external components to remove unwanted pulses.  $\overline{OCx}$  is not deglitched when the switch is turned off due to an overtemperature shutdown.



Copyright © 2016, Texas Instruments Incorporated

图 9-2. Typical Circuit for the  $\overline{OC}$  Pin (TPS2042B-Q1)

### 9.2.1.3 Application Curves

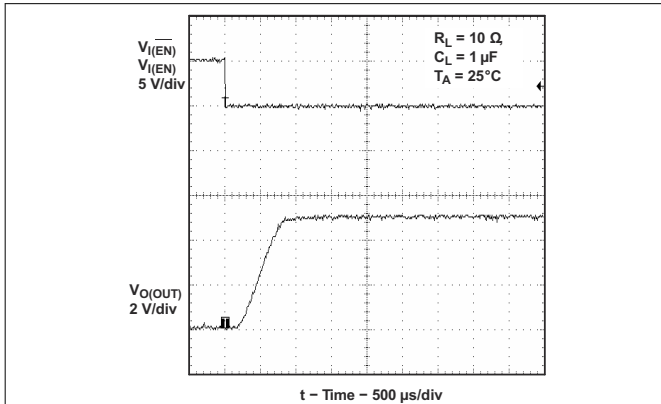


图 9-3. Turnon Delay and Rise Time With 1-µF Load

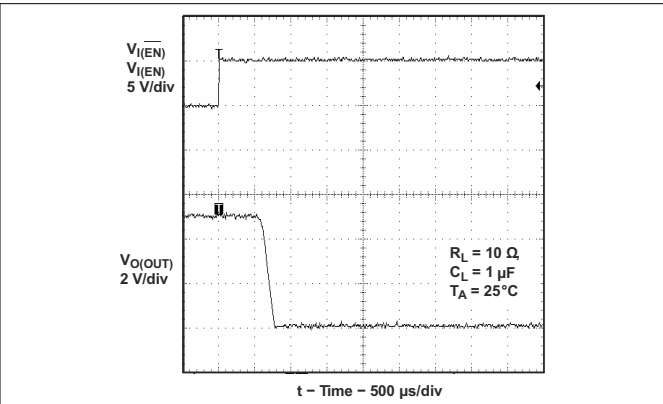


图 9-4. Turnoff Delay and Fall Time With 1-µF Load

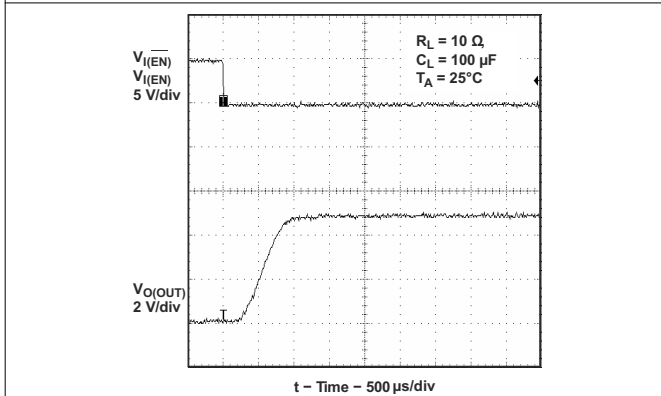


图 9-5. Turnon Delay and Rise Time With 100-µF Load

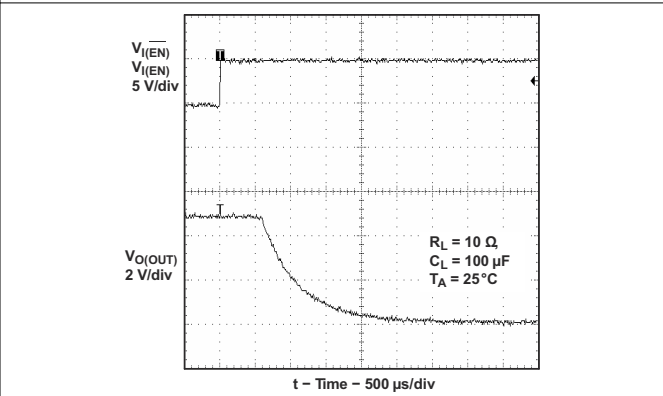


图 9-6. Turnoff Delay and Fall Time With 100-µF Load

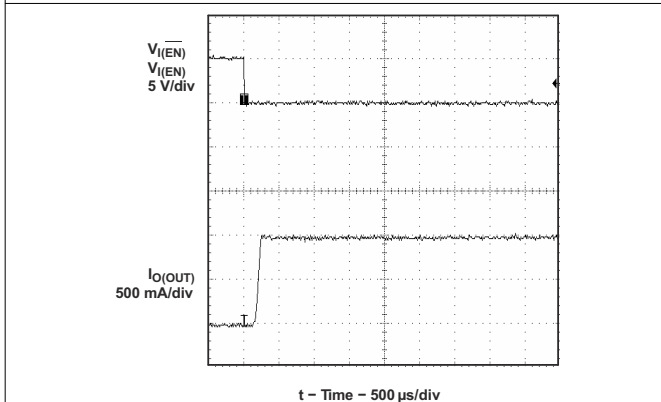


图 9-7. Short-Circuit Current, Device Enabled Into Short

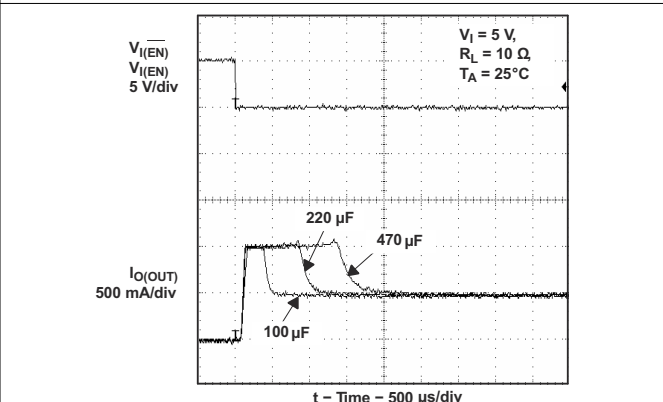
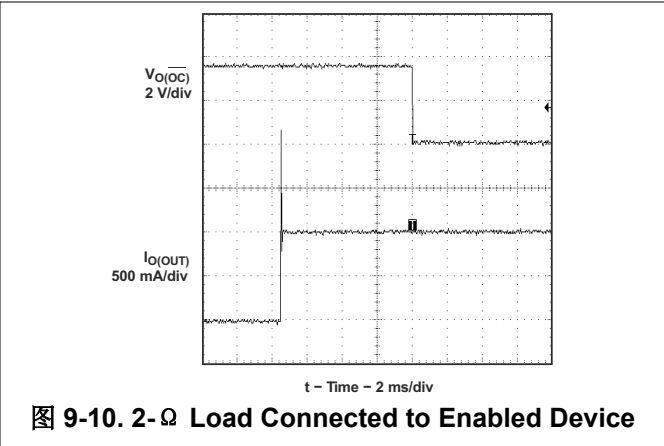
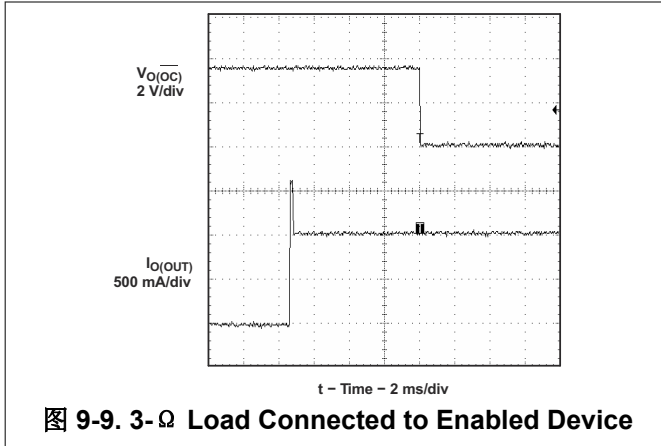


图 9-8. Inrush Current With Different Load Capacitance





### 9.2.2 Hosts and Self-Powered Hubs and Bus-Powered Hubs

Hosts and self-powered hubs have a local power supply that powers the embedded functions and the downstream ports (see 图 9-11). This power supply must provide from 5.25 V to 4.75 V to the board side of the downstream connection under full-load and no-load conditions. Hosts and SPHs are required to have current-limit protection and must report overcurrent conditions to the USB controller. Typical SPHs are desktop PCs, monitors, printers, and stand-alone hubs.

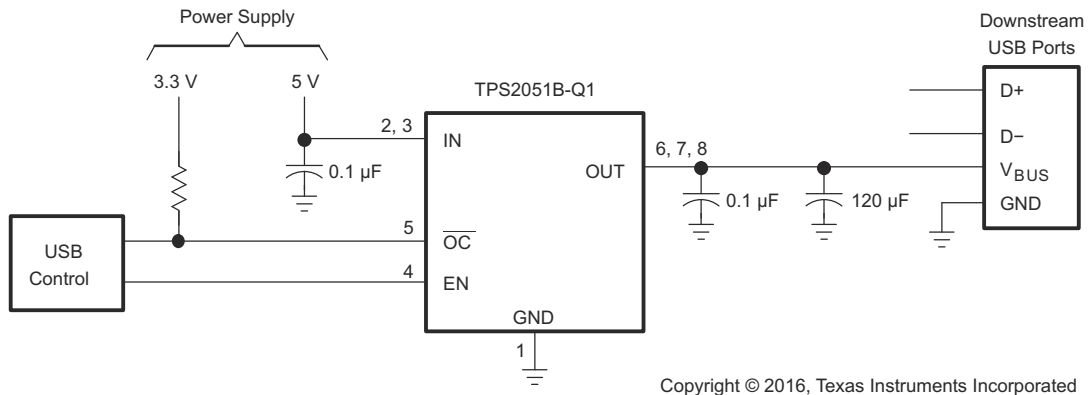


图 9-11. Typical One-Port USB Host or Self-Powered Hub

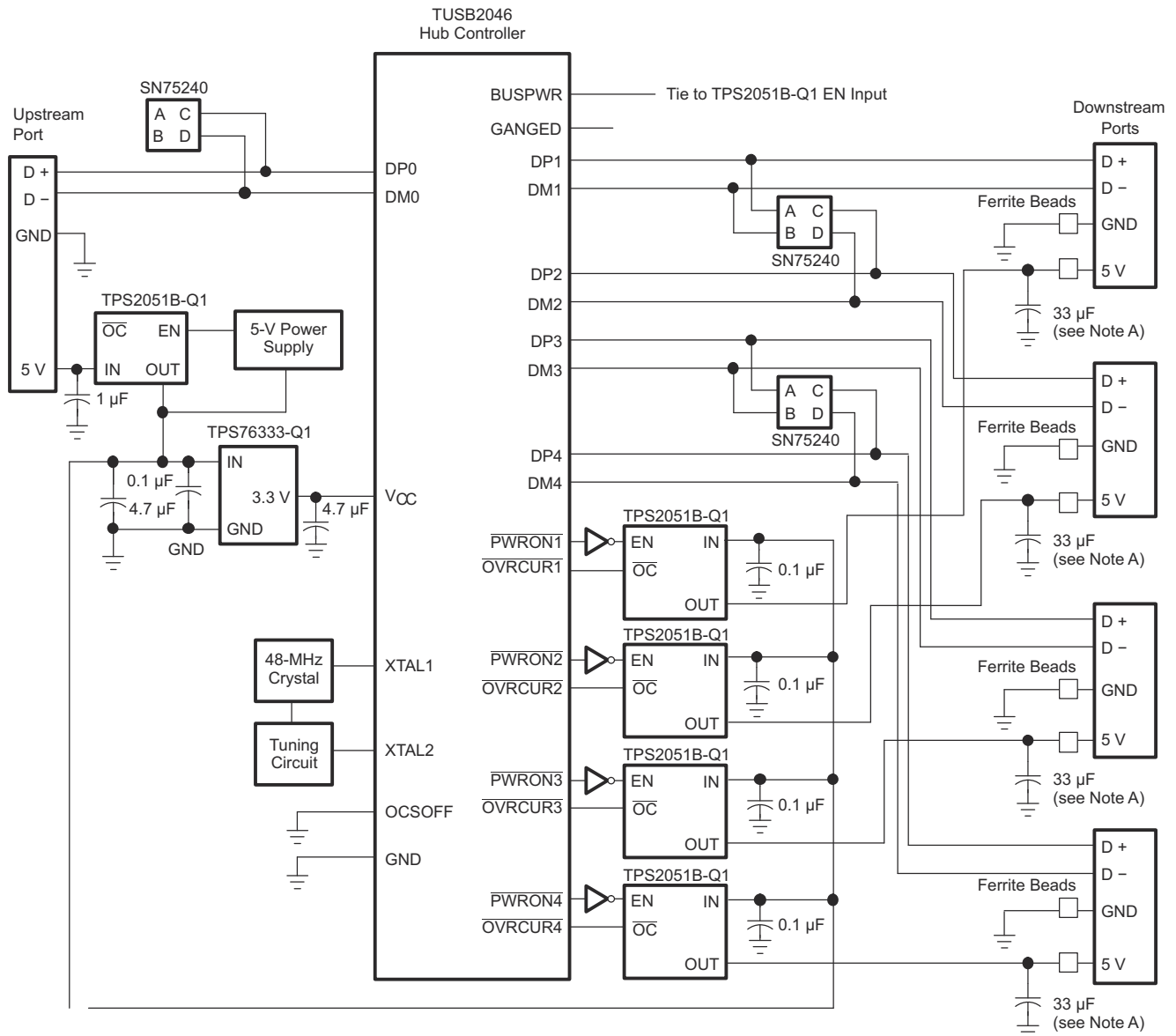
#### 9.2.2.1 Design Requirements

##### 9.2.2.1.1 USB Power-Distribution Requirements

USB can be implemented in several ways, and, regardless of the type of USB device being developed, several power-distribution features must be implemented.

- Hosts and self-powered hubs must:
  - Current-limit downstream ports
  - Report overcurrent conditions on USB  $V_{BUS}$
- Bus-powered hubs must:
  - Enable and disable power to downstream ports
  - Power up at < 100 mA
  - Limit inrush current (< 44 Ω and 10 μF)
- Functions must:
  - Limit inrush currents
  - Power up at < 100 mA

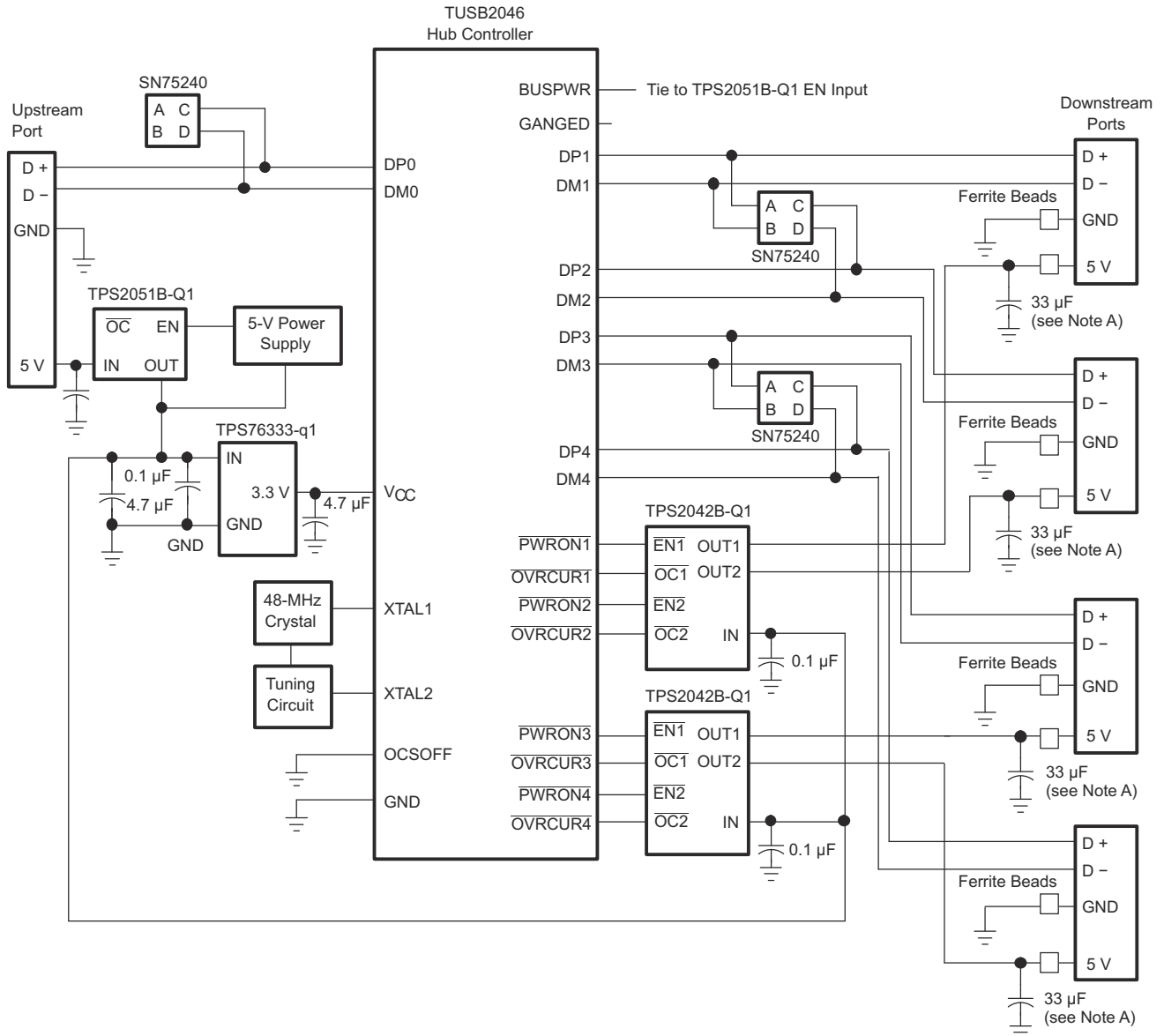
The feature set of the TPS204xB-Q1 and TPS205xB-Q1 allows them to meet each of these requirements. The integrated current-limiting and overcurrent reporting is required by hosts and self-powered hubs. The logic-level enable and controlled rise times meet the need of both input and output ports on bus-powered hubs, as well as the input ports for bus-powered functions (see [Figure 9-12](#) and [Figure 9-13](#)).



Copyright © 2016, Texas Instruments Incorporated

A. USB rev 1.1 requires 120 µF per hub.

**Figure 9-12. Hybrid Self-Powered or Bus-Powered Hub Implementation (TPS2051B-Q1)**



Copyright © 2016, Texas Instruments Incorporated

A. USB rev 1.1 requires 120 µF per hub.

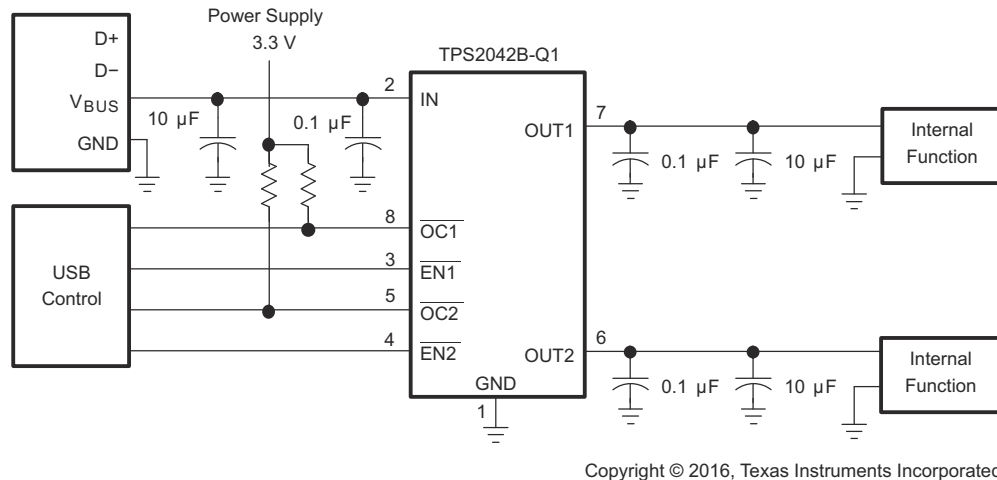
**图 9-13. Hybrid Self-Powered or Bus-Powered Hub Implementation (TPS2042B-Q1)**

### 9.2.2.2 Detailed Design Procedure

Bus-powered hubs obtain all power from upstream ports and often contain an embedded function. The hubs are required to power up with less than one unit load. The BPH usually has one embedded function, and power is always available to the controller of the hub. If the embedded function and hub require more than 100 mA on power up, the power to the embedded function may need to be kept off until enumeration is completed. This can be accomplished by removing power or by shutting off the clock to the embedded function. Power switching the embedded function is not necessary if the aggregate power draw for the function and controller is less than one unit load. The total current drawn by the bus-powered device is the sum of the current to the controller, the embedded function, and the downstream ports, and it is limited to 500 mA from an upstream port.

### 9.2.2.2.1 Low-Power Bus-Powered and High-Power Bus-Powered Functions

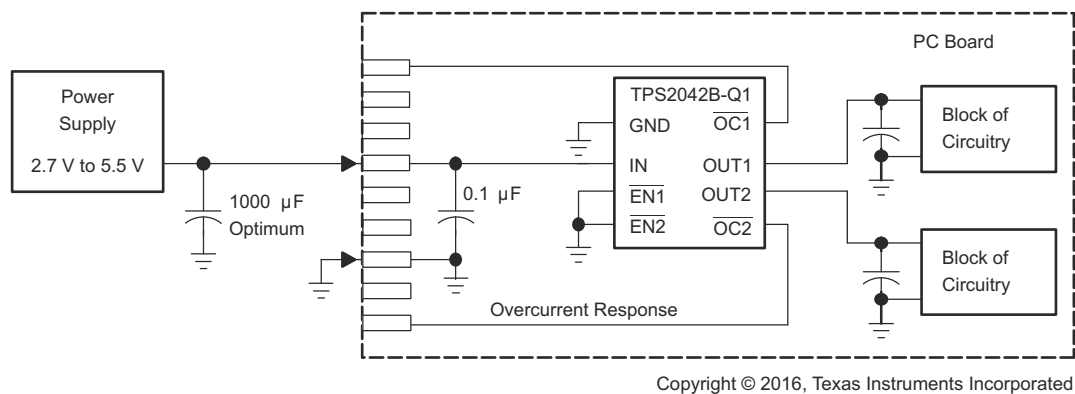
Both low-power and high-power bus-powered functions obtain all power from upstream ports; low-power functions always draw less than 100 mA; high-power functions must draw less than 100 mA at power up and can draw up to 500 mA after enumeration. If the load of the function is more than the parallel combination of 44  $\Omega$  and 10  $\mu\text{F}$  at power up, the device must implement inrush current limiting (see [图 9-14](#)).



**图 9-14. High-Power Bus-Powered Function (TPS2042B-Q1)**

### 9.2.3 Generic Hot-Plug Applications

In many applications, it may be necessary to remove modules or PC boards while the main unit is still operating. These are considered hot-plug applications. Such implementations require the control of current surges seen by the main power supply and the card being inserted. The most effective way to control these surges is to limit and slowly ramp the current and voltage being applied to the card, similar to the way in which a power supply normally turns on. Due to the controlled rise and fall times of the TPS204xB-Q1 and TPS205xB-Q1, these devices can be used to provide a softer start-up to devices being hot-plugged into a powered system. The UVLO feature of the TPS204xB-Q1 and TPS205xB-Q1 also ensures that the switch is off after the card has been removed, and that the switch is off during the next insertion. The UVLO feature ensures a soft start with a controlled rise time for every insertion of the card or module.



**图 9-15. Example Hot-Plug Implementation (TPS2042B-Q1)**

By placing the TPS204xB-Q1 or TPS205xB-Q1 between the  $V_{CC}$  input and the rest of the circuitry, the input power reaches these devices first after insertion. The typical rise time of the switch is approximately 1 ms, providing a slow voltage ramp at the output of the device. This implementation controls system surge currents and provides a hot-plugging mechanism for any device.

### 9.2.3.1 Design Requirements

For this design example, use the parameters listed in [表 9-2](#) as the input parameters.

**表 9-2. Design Parameters**

PARAMETER	VALUE
Input voltage	5 V
Output1 voltage	5 V
Output2 voltage	5 V
Output1 current	0.5 A
Output2 current	0.5 A

### 9.2.3.2 Detailed Design Procedure

To begin the design process a few parameters must be decided upon. The designer must know the following:

- Normal input operation voltage
- Current limit

Input and output capacitance improves the performance of the device; the actual capacitance must be optimized for the particular application. For all applications, TI recommends a 0.1  $\mu$ F or greater ceramic bypass capacitor between IN and GND, as close to the device as possible for local noise decoupling. This precaution reduces ringing on the input due to power-supply transients. Additional input capacitance may be required on the input to reduce voltage undershoot from exceeding the UVLO of other load share one power rail with TPS2042B-Q1 device or overshoot from exceeding the absolute-maximum voltage of the device during heavy transient conditions. This is especially important during bench testing when long, inductive cables are used to connect the evaluation board to the bench power supply. Output capacitance is not required, but TI recommends placing a high-value electrolytic capacitor on the output pin when large transient currents are expected on the output to reduce the undershoot, which is caused by the inductance of the output power bus just after a short has occurred and the TPS2042B-Q1 device has abruptly reduced OUT current. Energy stored in the inductance drives the OUT voltage down and potentially negative as it discharges.

## 10 Power Supply Recommendations

TI recommends a 0.01- $\mu$ F to 0.1- $\mu$ F ceramic bypass capacitor close to the device between IN and GND. TI recommends placing a high-value electrolytic capacitor on the output pins when the output load is heavy. This precaution reduces power-supply transients that may cause ringing on the input. Additionally, bypassing the output with a 0.01- $\mu$ F to 0.1- $\mu$ F ceramic capacitor improves the immunity of the device to short-circuit transients. See [图 9-1](#).

## 11 Layout

### 11.1 Layout Guidelines

- Place the 100-nF bypass capacitor near the IN and GND pins and make the connections using a low-inductance trace.
- TI recommends placing a high-value electrolytic capacitor and a 100-nF bypass capacitor on the output pin when large transient currents are expected on the output.

### 11.2 Layout Example

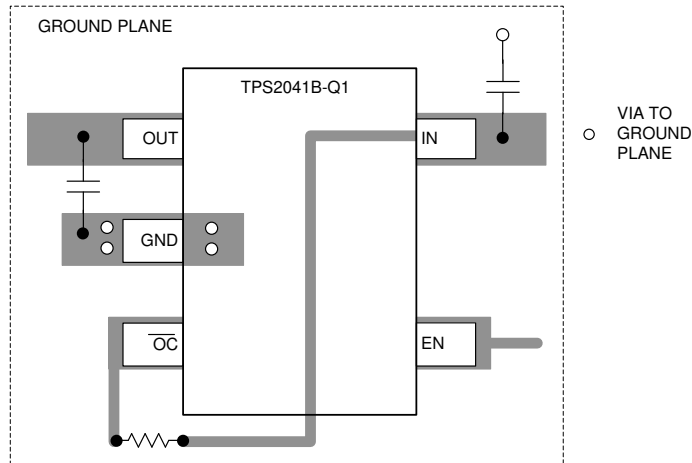


图 11-1. Layout Recommendation

### 11.3 Thermal Considerations

The low on-resistance on the N-channel MOSFET allows the small surface-mount packages to pass large currents. The thermal resistances of these packages are high compared to those of power packages; it is good design practice to check power dissipation and junction temperature. Begin by determining the  $r_{DS(ON)}$  of the N-channel MOSFET relative to the input voltage and operating temperature. As an initial estimate, use the highest operating ambient temperature of interest and read  $r_{DS(ON)}$  from 图 6-9. Using this value, the power dissipation per switch can be calculated by 方程式 1:

$$P_D = r_{DS(ON)} \times I^2 \quad (1)$$

Multiply this number by the number of switches being used. This step renders the total power dissipation from the N-channel MOSFETs.

Finally, calculate the junction temperature with 方程式 2:

$$T_J = P_D \times R_{\theta JA} + T_A \quad (2)$$

where

- $T_A$  = Ambient temperature °C
- $R_{\theta JA}$  = Thermal resistance
- $P_D$  = Total power dissipation based on number of switches being used.

Compare the calculated junction temperature with the initial estimate. If they do not agree within a few degrees, repeat the calculation, using the calculated value as the new estimate. Two or three iterations are generally sufficient to get a reasonable answer.

## 12 Device and Documentation Support

### 12.1 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

**表 12-1. Related Links**

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
TPS2041B-Q1	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>
TPS2042B-Q1	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>
TPS2051B-Q1	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>

### 12.2 接收文档更新通知

要接收文档更新通知，请导航至 [ti.com](http://ti.com) 上的器件产品文件夹。点击 [订阅更新](#) 进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

### 12.3 支持资源

TI E2E™ [支持论坛](#) 是工程师的重要参考资料，可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题可获得所需的快速设计帮助。

链接的内容由各个贡献者“按原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参阅 TI 的 [《使用条款》](#)。

### 12.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

所有商标均为其各自所有者的财产。

### 12.5 静电放电警告



静电放电 (ESD) 会损坏这个集成电路。德州仪器 (TI) 建议通过适当的预防措施处理所有集成电路。如果不遵守正确的处理和安装程序，可能会损坏集成电路。

ESD 的损坏小至导致微小的性能降级，大至整个器件故障。精密的集成电路可能更容易受到损坏，这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

### 12.6 术语表

[TI 术语表](#) 本术语表列出并解释了术语、首字母缩略词和定义。

## 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

**PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TPS2041BQDBVRQ1	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	PLIQ	<a href="#">Samples</a>
TPS2042BQDRQ1	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2042B	<a href="#">Samples</a>
TPS2051BQDRQ1	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2051BQ	<a href="#">Samples</a>

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:**The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.



In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

**TAPE AND REEL INFORMATION**

**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS2041BQDBVRQ1	SOT-23	DBV	5	3000	179.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TPS2042BQDRQ1	SOIC	D	8	2500	330.0	12.5	6.4	5.2	2.1	8.0	12.0	Q1
TPS2051BQDRQ1	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

**TAPE AND REEL BOX DIMENSIONS**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS2041BQDBVRQ1	SOT-23	DBV	5	3000	200.0	183.0	25.0
TPS2042BQDRQ1	SOIC	D	8	2500	340.5	338.1	20.6
TPS2051BQDRQ1	SOIC	D	8	2500	340.5	338.1	20.6

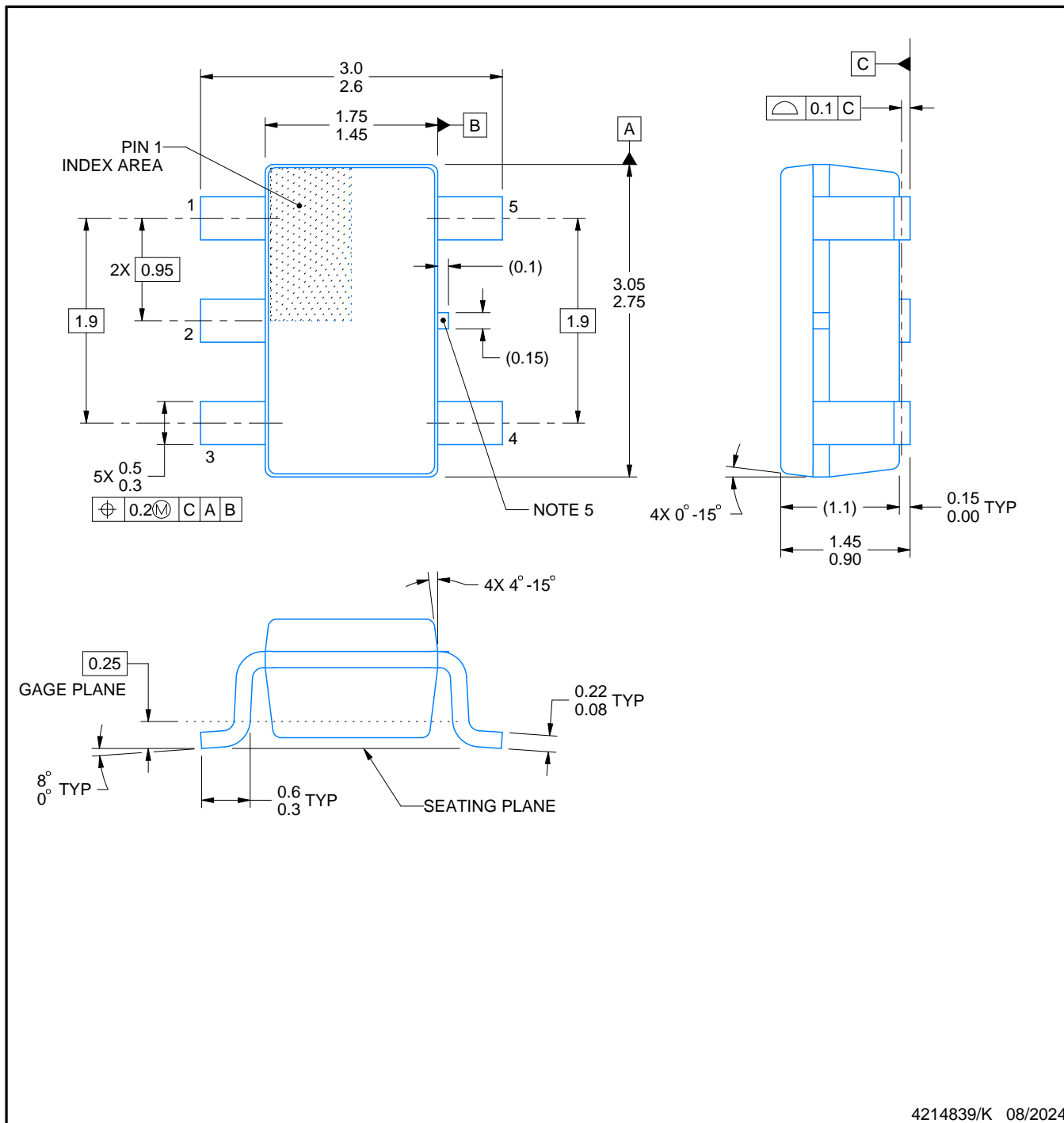
# DBV0005A



# PACKAGE OUTLINE

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



## NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. Reference JEDEC MO-178.
4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.
5. Support pin may differ or may not be present.

# EXAMPLE BOARD LAYOUT

DBV0005A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



LAND PATTERN EXAMPLE  
EXPOSED METAL SHOWN  
SCALE:15X



SOLDER MASK DETAILS

4214839/K 08/2024

NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

# EXAMPLE STENCIL DESIGN

DBV0005A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR

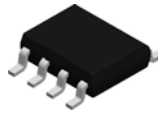


SOLDER PASTE EXAMPLE  
BASED ON 0.125 mm THICK STENCIL  
SCALE:15X

4214839/K 08/2024

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.



D0008A

# PACKAGE OUTLINE

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



4214825/C 02/2019

NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MS-012, variation AA.

# EXAMPLE BOARD LAYOUT

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



LAND PATTERN EXAMPLE  
EXPOSED METAL SHOWN  
SCALE:8X



SOLDER MASK DETAILS

4214825/C 02/2019

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



# EXAMPLE STENCIL DESIGN

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE  
BASED ON .005 INCH [0.125 MM] THICK STENCIL  
SCALE:8X

4214825/C 02/2019

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

## 重要声明和免责声明

TI“按原样”提供技术和可靠性数据（包括数据表）、设计资源（包括参考设计）、应用或其他设计建议、网络工具、安全信息和其他资源，不保证没有瑕疵且不做任何明示或暗示的担保，包括但不限于对适销性、某特定用途方面的适用性或不侵犯任何第三方知识产权的暗示担保。

这些资源可供使用 TI 产品进行设计的熟练开发人员使用。您将自行承担以下全部责任：(1) 针对您的应用选择合适的 TI 产品，(2) 设计、验证并测试您的应用，(3) 确保您的应用满足相应标准以及任何其他功能安全、信息安全、监管或其他要求。

这些资源如有变更，恕不另行通知。TI 授权您仅可将这些资源用于研发本资源所述的 TI 产品的应用。严禁对这些资源进行其他复制或展示。您无权使用任何其他 TI 知识产权或任何第三方知识产权。您应全额赔偿因在这些资源的使用中对 TI 及其代表造成的任何索赔、损害、成本、损失和债务，TI 对此概不负责。

TI 提供的产品受 [TI 的销售条款](#) 或 [ti.com](#) 上其他适用条款/TI 产品随附的其他适用条款的约束。TI 提供这些资源并不会扩展或以其他方式更改 TI 针对 TI 产品发布的适用的担保或担保免责声明。

TI 反对并拒绝您可能提出的任何其他或不同的条款。

邮寄地址：Texas Instruments, Post Office Box 655303, Dallas, Texas 75265

Copyright © 2024，德州仪器 (TI) 公司